INFORMATION DISCLOSURE STATEMENT BY APPLICANT ( Not for submission under 37 CFR 1.99)	Application Number		10594045		
	Filing Date		2007-06-27		
	First Named Inventor Koji N		Nakayama		
	Art Unit		2811		
	Examiner Name	Lynne	e Ann Gurley		
	Attorney Docket Numb	er	1217-062849		
	/				

					U.S.I	PATENTS			Remove		
Examiner Initial*	Cite No	Patent Number	Kind Code <sup>1</sup>	Issue D	)ate	Name of Pate of cited Docu	Releva		Lines where ges or Relev		
	1	6849874	B2	2005-02	?-01	Sumakeris et a					
If you wisl	n to ac	⊥ dd additional U.S. Pater	⊥ nt citatio	l n inform	ation pl	ease click the	Add button.		Add		
U.S.PATENT APPLICATION PUBLICATIONS Remove											
Examiner Initial*	Cite No	Publication Number	Kind Code <sup>1</sup>	Publica Date	tion Name of Patentee or Applicant of cited Document		Releva		Lines where ges or Relev		
	1										
If you wisl	n to a	dd additional U.S. Publi	shed Ap	plication	n citatio	ո information բ	please click the Add	d button	Add		
FOREIGN PATENT DOCUMENTS Remove											
Examiner Initial*	Cite No	Foreign Document Number <sup>3</sup>	Country Code <sup>2</sup> i		Kind Code <sup>4</sup>	Publication Date	Applicant of cited Postument		vhere Rel	or Relevant	<b>T</b> 5
	1	10261615	JP		А	1998-09-29	Fuji Electric Co Ltd				
	2	2002261041	JP		А	2002-09-13	Shikusuon et al.				
	3	2001077030	JP		А	2001-03-23	Sanyo Electric et al				

## INFORMATION DISCLOSURE STATEMENT BY APPLICANT

( Not for submission under 37 CFR 1.99)

Application Number		10594045			
Filing Date		2007-06-27			
First Named Inventor	Koji N	Koji Nakayama			
Art Unit		2811			
Examiner Name	Lynne Ann Gurley				
Attorney Docket Number		1217-062849			

	4	03038876	WO	A1	2003-05-08	Cree Inc.				
If you wish to add additional Foreign Patent Document citation information please click the Add button Add										
NON-PATENT LITERATURE DOCUMENTS Remove										
Examiner Initials*	Cite No	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc), date, pages(s), volume-issue number(s), publisher, city and/or country where published.								
	1	BONDOKOV, ROBERT T. ET AL., "Influence of Structural Defects on the Polishing of Silicon Carbide Single Crystal Wafers", Japanese Journal of Applied Physics, Vol. 43, No. 1, 2004, pp. 43-49, Abstract only (1 p.)								
	2	LENDENMANN, H. ET AL., "High-Power SiC Diodes: Characteristics, Reliability and Relation to Material Defects", Materials Science Forum, Vols. 389-393 (2002), pp. 1259-1264, Trans Tech Publications, Switzerland								
	3	LEE, K.S. ET AL., "Surface Preparation of 6H-Silicon Carbide Substrates for Growth of High-Quality SiC Epilayers", Materials Science Forum, Vols. 457-460 (2004), pp. 797-800								
If you wis	h to ac	dd additional non-paten	t literature docur	ment cit	tation informati	on please click the Add b	outton Add			
EXAMINER SIGNATURE										
Examiner Signature Date Considered										
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through a citation if not in conformance and not considered. Include copy of this form with next communication to applicant.										
<sup>1</sup> See Kind Codes of USPTO Patent Documents at <a href="https://www.USPTO.GOV">www.USPTO.GOV</a> or MPEP 901.04. <sup>2</sup> Enter office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>3</sup> For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>4</sup> Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. <sup>5</sup> Applicant is to place a check mark here if English language translation is attached.										